

Notice of References Cited	Application/Control No. 10/780,224		Applicant(s)/Patent Under Reexamination ZHENG, FANG-ZHEN	
	Examiner Patrick M. Buechner		Art Unit 3754	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-1,314,199	08-1919	Jarvis	102/528
X	B	US-2,701,078	02-1955	BOWMAN EDWARD W	141/321
X	C	US-3,301,525	01-1967	CHERNAK JOHN A; et. al.	251/331
X	D	US-5,449,144	09-1995	Kowalics, Raymond P.	251/99
X	E	US-5,470,044	11-1995	Chi, James	251/98
X	F	US-5,762,317	06-1998	Frahm et al.	251/95
X	G	US-6,082,598	07-2000	Lee, SungKeun	222/509
X	H	US-6,086,045	07-2000	Moon, Young Mu	251/335.1
X	I	US-6,793,195	09-2004	Dou, Hai	251/96
X	J	US-6,880,797	04-2005	Yui, George M.	251/103
X	K	US-6,868,994	03-2005	Kawolics, Raymond P.	222/517
X	L	US-D378,400	03-1997	Kowalics, Raymond P.	D23/238
X	M	US-D482,235	11-2003	Yui, George	D7/398

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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